

design, create and inspect micro and nano-scale functional prototype devices and create 3D Nanoprototyping with a DualBeam, sharp, refined and charge-free contrast obtained from up to 6 integrated in-column and below-the-lens detectors, can mill difficult charging samples with charge neutralizer.

*Docket Number:* 15–034. *Applicant:* Purdue University, West Lafayette, IN 47907. *Instrument:* Diode-Pumped Solid-State Laser. *Manufacturer:* Edgewave GmbH, Germany. *Intended Use:* See notice at 80 FR 44936–37, July 28, 2015. *Comments:* None received. *Decision:* Approved. We know of no instruments of equivalent scientific value to the foreign instruments described below, for such purposes as this is intended to be used, that was being manufactured in the United States at the time of order. *Reasons:* The instrument will be used to enhance the fundamental understanding of propellant combustion so that safer and higher performance solid propellants can be designed and developed. The instrument is to be used for the measurement of flame radical species in propellant flames in real-time, using high-frame-rate (10–40kHz) imaging of the flame radical OH, produced in the reaction zone. The OH distribution is used to determine the burning mode for the propellant, and the laser system will give the capability to obtain high-frame-rate images of other propellants. The primary technique is high-frame-rate planar laser-induced fluorescence (PLIF) imaging. The UV laser from a Credo dye laser, pumped by the Edgewave DPSS laser, is formed into a focused sheet using a combination of spherical and cylindrical lenses. The frequency of the UV beam is then tuned to a resonance transition for the OH radical and the OH radical is pumped from the ground state to an excited electronic state by absorbing a photon from the laser sheet. Once in the excited state, the OH radical can decay by emitting a photon (fluorescence). The fluorescence light is imaged using a high-frame-rate intensified CMOS camera to produce an image of the OH distribution in the laser sheet, providing both time- and space-resolved information on the laser process. No domestic instruments have the required power, rep rate, and pulse length on the order of 10 nanoseconds.

**Gregory W. Campbell,**

*Director, Subsidies Enforcement Office, Enforcement and Compliance.*

[FR Doc. 2015–24468 Filed 9–28–15; 8:45 am]

**BILLING CODE 3510-DS-P**

**DEPARTMENT OF COMMERCE**

**International Trade Administration**

**Oregon State University, et al.; Notice of Consolidated Decision on Applications for Duty-Free Entry of Electron Microscope**

This is a decision consolidated pursuant to Section 6(c) of the Educational, Scientific, and Cultural Materials Importation Act of 1966 (Pub. L. 89–651, as amended by Pub. L. 106–36; 80 Stat. 897; 15 CFR part 301). Related records can be viewed between 8:30 a.m. and 5:00 p.m. in Room 3720, U.S. Department of Commerce, 14th and Constitution Avenue NW., Washington, DC.

*Docket Number:* 15–019. *Applicant:* Oregon State University, Corvallis, OR 97331–2104. *Instrument:* Electron Microscope. *Manufacturer:* FEI Company, Czech Republic. *Intended Use:* See notice at 80 FR 44936, July 28, 2015.

*Docket Number:* 15–021. *Applicant:* The City University of New York, New York, NY 10017. *Instrument:* Electron Microscope. *Manufacturer:* FEI Company, Japan. *Intended Use:* See notice at 80 FR 44936, July 28, 2015.

*Docket Number:* 15–023. *Applicant:* Idaho National Laboratory, Idaho Falls, ID 83415. *Instrument:* Focused Ion Beam (FIB) Microscope. *Manufacturer:* FEI, Czech Republic. *Intended Use:* See notice at 80 FR 44936, July 28, 2015.

*Docket Number:* 15–025. *Applicant:* The Rockefeller University, New York, NY 10065. *Instrument:* Electron Microscope. *Manufacturer:* FEI Company, the Netherlands. *Intended Use:* See notice at 80 FR 44936–37, July 28, 2015.

*Docket Number:* 15–026. *Applicant:* University of Delaware, Newark, DE 19716. *Instrument:* Electron Microscope. *Manufacturer:* FEI Company, Brno, Czech Republic. *Intended Use:* See notice at 80 FR 44936–37, July 28, 2015.

*Docket Number:* 15–028. *Applicant:* University of California, Irvine, Irvine, CA 92697–2575. *Instrument:* Electron Microscope. *Manufacturer:* JEOL, Ltd., Japan. *Intended Use:* See notice at 80 FR 44936–47, July 28, 2015.

*Docket Number:* 15–030. *Applicant:* Washington State University, Pullman, WA 99164–1020. *Instrument:* MSM400 Yeast Tetrad Dissection Microscope. *Manufacturer:* Singer Instruments, United Kingdom. *Intended Use:* See notice at 80 FR 44936–37, July 28, 2015.

*Docket Number:* 15–033. *Applicant:* Battelle Memorial Institute, Richland, WA 99354. *Instrument:* Electron Microscope. *Manufacturer:* FEI

Company, the Netherlands. *Intended Use:* See notice at 80 FR 44936–38, July 28, 2015.

*Comments:* None received. *Decision:* Approved. No instrument of equivalent scientific value to the foreign instrument, for such purposes as this instrument is intended to be used, is being manufactured in the United States at the time the instrument was ordered. *Reasons:* Each foreign instrument is an electron microscope and is intended for research or scientific educational uses requiring an electron microscope. We know of no electron microscope, or any other instrument suited to these purposes, which was being manufactured in the United States at the time of order of each instrument.

**Gregory W. Campbell,**

*Director, Subsidies Enforcement Office, Enforcement and Compliance.*

[FR Doc. 2015–24466 Filed 9–28–15; 8:45 am]

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**DEPARTMENT OF COMMERCE**

**National Oceanic and Atmospheric Administration**

**RIN 0648-XE175**

**Marine Fisheries Advisory Committee Meeting**

**AGENCY:** National Marine Fisheries Service (NMFS), National Oceanic and Atmospheric Administration (NOAA), Commerce.

**ACTION:** Notice of open public meeting.

**SUMMARY:** This notice sets forth the proposed schedule and agenda of a forthcoming meeting of the Marine Fisheries Advisory Committee (MAFAC). The members will discuss and provide advice on issues outlined under **SUPPLEMENTARY INFORMATION** below.

**DATES:** The meeting will be held October 13–15, 2015, from 8:30 a.m. to 5 p.m.

**ADDRESS:** The meeting will be held at the Sheraton Silver Spring Hotel, 8777 Georgia Ave, Silver Spring, MD 20910; 301–589–0800.

**FOR FURTHER INFORMATION CONTACT:** Jennifer Lukens, MAFAC Executive Director; (301) 427–8004; email: [Jennifer.Lukens@noaa.gov](mailto:Jennifer.Lukens@noaa.gov).

**SUPPLEMENTARY INFORMATION:** As required by section 10(a)(2) of the Federal Advisory Committee Act, 5 U.S.C. App. 2, notice is hereby given of a meeting of MAFAC. The MAFAC was established by the Secretary of Commerce (Secretary), and, since 1971,